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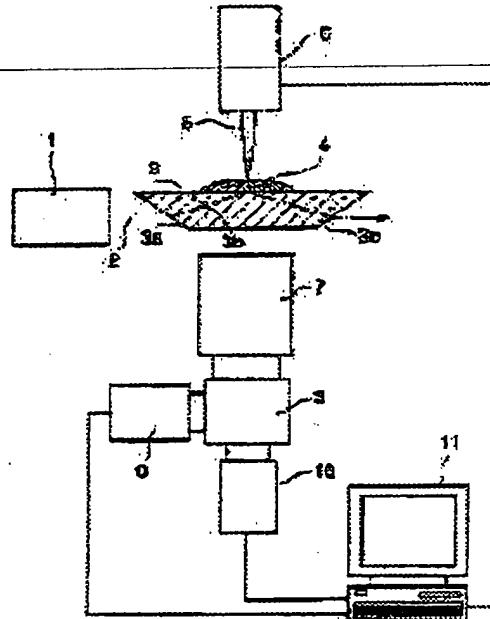
(54) METHOD AND DEVICE OF TESTING CHROMOSOME

(57)Abstract:

PROBLEM TO BE SOLVED: To provide a method of

testing chromosomes capable of observing gene sequence and state in high resolving power of frequencies less than those used in observation.

SOLUTION: A) A chromosome 4 is labeled with a fluorescent substance. B) Under the condition that evanescent light is generated on the surface of the chromosome 4, the chromosome 4 is irradiated with laser light 2 which are not absorbed in fluorescent substances. C) A probe 5 with a non-linear optical substance is brought close to the chromosome 4, and then non-linear optical substance is subjected to evanescent light. Here, D) object light to be detected generated by the mutual action between evanescent light and the non-linear optical substance is selected and detected. E) The probe 5 is moved along the chromosome 4 for scanning, and above-mentioned C) and D) are repeated. F) The characteristic value of the above-mentioned object light to be detected is visually displayed correspondingly to the location of the probe 5 in scanning.



LEGAL STATUS

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